

RELIABILITY MONITOR

PROCESS: 0.8 μ m Double Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2153	A7	JUN '98	P22294	9740	ANAM-KOREA (AICL)	DN725561AAB	44 PIN PLCC	48	237	0
DS2153Q	A7	MAR '98	P22292	9734	ANAM-KOREA (AICL)	DN720030AAB	44 PIN PLCC	48	237	0
DS2153Q	A7	SEPT.'98	P22556	9749	ANAM-KOREA (AICL)	DN733468AAB	44 PIN PLCC	48	236	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2153	A7	JUN '98	P22334	9740	ANAM-KOREA (AICL)	DN725561AAB	44 PIN PLCC	336	76	0
DS2153	A7	JUN '98	P22334	9740	ANAM-KOREA (AICL)	DN725561AAB	44 PIN PLCC	1000	76	0
DS2153Q	A7	MAR '98	P22331	9734	ANAM-KOREA (AICL)	DN720030AAB	44 PIN PLCC	336	77	0
DS2153Q	A7	MAR '98	P22331	9734	ANAM-KOREA (AICL)	DN720030AAB	44 PIN PLCC	1000	77	0

TOTALS FOR: 0.8 μ m Double Poly, Single Metal FAIL RATE (Fits): 16 DEVICE HRS: 5.78E+07 0

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PROCESS: 0.8 μ m Single Poly, Double Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1302	C1	DEC '97	P21627	9745	ANAM-KOREA (AICL)	DN736077AAC	8 PIN SOIC	48	232	0
DS1302	A3	JUN '98	P22282	9808	ANAM-KOREA (AICL)	DN750310AB	8 PIN SOIC	48	234	0
DS1302	C1	MAR '98	P21826	9808	HYUNDAI-KOREA (HEI)	DL750312ABA	8 PIN SOIC	48	229	0
DS1315	B1	SEP '98	P22496	9825	ANAM-PI (AAPI)	DK806519AAA	16 PIN PDIP	48	234	0
DS17485	A2	MAY '98	P22308	9814	ANAM-KOREA (AICL)	DN803023AAD	24 PIN SOIC	48	230	0
DS17485	A2	FEB.'98	P22032	9730	ANAM-KOREA (AICL)	DN713701AAE	24 PIN SOIC	48	230	0
DS17485	A2	AUG '98	P22472	9819	ANAM-KOREA (AICL)	DN807687AAA	24 PIN SOIC	48	233	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1302	A3	JUN '98	P22349	9808	ANAM-KOREA (AICL)	DN750310AB	8 PIN SOIC	336	77	0
DS1302	C1	DEC '97	P21731	9745	ANAM-KOREA (AICL)	DN736077AAC	8 PIN SOIC	336	77	0
DS1302	A3	JUN '98	P22349	9808	ANAM-KOREA (AICL)	DN750310AB	8 PIN SOIC	1000	77	0
DS1302	C1	DEC '97	P21731	9745	ANAM-KOREA (AICL)	DN736077AAC	8 PIN SOIC	1000	77	0
DS1302	C1	MAR '98	P21972	9808	HYUNDAI-KOREA (HEI)	DL750312ABA	8 PIN SOIC	336	75	0
DS1302	C1	MAR '98	P21972	9808	HYUNDAI-KOREA (HEI)	DL750312ABA	8 PIN SOIC	1000	75	0
DS17485	A2	MAY '98	P22467	9814	ANAM-KOREA (AICL)	DN803023AAD	24 PIN SOIC	336	77	0
DS17485	A2	FEB.'98	P22303	9730	ANAM-KOREA (AICL)	DN713701AAE	24 PIN SOIC	336	77	0
DS17485	A2	FEB.'98	P22303	9730	ANAM-KOREA (AICL)	DN713701AAE	24 PIN SOIC	1000	76	0

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DS17485 A2 MAY '98 P22467 9814 ANAM-KOREA (AICL) DN803023AAD 24 PIN SOIC 1000 77 0

TOTALS FOR: 0.8 μ m Single Poly, Double Metal FAIL RATE (Fits): 9 DEVICE HRS: 1.03E+08 0

RELIABILITY MONITOR

PROCESS: 0.8 µm Single Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1232S	C1	JUL '98	P22324	9821	HYUNDAI-KOREA (HEI)	DL809263AAC	16 PIN SOIC	48	234	0
DS1620	D1	SEPT. '98	P22599	9746	ALPHTK-BANGKOK(NSE	DJ711527ABD	8PN SOIC, 208MIL	48	230	0
DS1620	D1	JUN '98	P22198	9741	ALPHTK-BANGKOK(NSE	DJ723284AAF	8PN SOIC, 208MIL	48	237	0
DS1621	A7	SEPT.'98	P22590	9807	ANAM-KOREA (AICL)	DN744346ABA	8 PIN SOIC	48	236	0
DS1621	A5	MAR '98	P22276	9749	CARSEM	DM705419AB	8 PIN SOIC	48	230	0
DS1621	A5	JUN '98	P22200	9745	CARSEM	DM734572AA	8 PIN SOIC	48	237	0
DS1621	A5	DEC '97	P21367	9740	CARSEM	DM727709AA	8 PIN SOIC	48	236	0
DS21S07	E	FEB '98	P21637	9802	CARSEM	DM741735AB	20 PIN TSSOP	48	234	0
DS21S07	E	MAY '98	P22171	9815	CARSEM	DM805323AA	20 PIN TSSOP	48	234	0
DS21S07	E	AUG '98	P22466	9820	CARSEM	DM807703AA	20 PIN TSSOP	48	234	0
DS2401	B2	JUN '98	P22123	9805	CARSEM	DM743297AD	T0-92	48	234	0
DS2401	B2	MAR '98	P22152	9802	CARSEM	DM741755AC	T0-92	48	234	0
DS2401	B2	SEPT. '98	P22504	9814	CARSEM	DM747716AC	T0-92	48	234	0
DS2502	B4	JUN '98	P22251	9814	CARSEM	DM751356AFA	8 PIN SOIC	48	193	0
DS2502	B6	SEPT.'98	P22573	9827	CARSEM	DM811458AA	8 PIN SOIC	48	233	0
DS80320	B5	JUL '98	P22230	9815	ANAM-PI (AAPI)	DK804253AAA	40 PIN PDIP	48	234	0
DS80320	B5	APR '98	P21893	9810	ANAM-PI (AAPI)	DK748103AA	40 PIN PDIP	48	234	0

RELIABILITY MONITOR

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1232S	C1	JUL '98	P22370	9821	HYUNDAI-KOREA (HEI)	DL809263AAC	16 PIN SOIC	336	77	0
DS1232S	C1	JUL '98	P22370	9821	HYUNDAI-KOREA (HEI)	DL809263AAC	16 PIN SOIC	1000	77	0
DS1620	D1	JUN '98	P22287	9741	ALPHTK-BANGKOK(NSE	DJ723284AAF	8PN SOIC, 208MIL	336	77	0
DS1620	D1	JUN '98	P22287	9741	ALPHTK-BANGKOK(NSE	DJ723284AAF	8PN SOIC, 208MIL	1000	77	0
DS1621	A5	MAR '98	P22342	9749	CARSEM	DM705419AB	8 PIN SOIC	336	68	0
DS1621	A5	DEC '97	P21727	9740	CARSEM	DM727709AA	8 PIN SOIC	336	77	0
DS1621	A5	JUN '98	P22283	9745	CARSEM	DM734572AA	8 PIN SOIC	336	71	0
DS1621	A5	MAR '98	P22342	9749	CARSEM	DM705419AB	8 PIN SOIC	1000	67	0
DS1621	A5	DEC '97	P21727	9740	CARSEM	DM727709AA	8 PIN SOIC	1000	77	0
DS1621	A5	JUN '98	P22283	9745	CARSEM	DM734572AA	8 PIN SOIC	1000	71	0
DS21S07	E	FEB '98	P21694	9802	CARSEM	DM741735AB	20 PIN TSSOP	336	77	0
DS21S07	E	MAY '98	P22242	9815	CARSEM	DM805323AA	20 PIN TSSOP	336	77	0
DS21S07	E	MAY '98	P22242	9815	CARSEM	DM805323AA	20 PIN TSSOP	1000	77	0
DS21S07	E	FEB '98	P21694	9802	CARSEM	DM741735AB	20 PIN TSSOP	1000	77	0
DS2401	B2	JUN '98	P22157	9805	CARSEM	DM743297AD	T0-92	336	77	0
DS2401	B2	MAR '98	P22162	9802	CARSEM	DM741755AC	T0-92	336	77	0
DS2401	B2	MAR '98	P22162	9802	CARSEM	DM741755AC	T0-92	1000	77	0
DS2401	B2	JUN '98	P22157	9805	CARSEM	DM743297AD	T0-92	1000	77	0
DS80320	B5	APR '98	P21964	9810	ANAM-PI (AAPI)	DK748103AA	40 PIN PDIP	336	77	0
DS80320	B5	JUL '98	P22309	9815	ANAM-PI (AAPI)	DK804253AAA	40 PIN PDIP	336	77	0
DS80320	B5	JUL '98	P22309	9815	ANAM-PI (AAPI)	DK804253AAA	40 PIN PDIP	1000	77	0
DS80320	B5	APR '98	P21964	9810	ANAM-PI (AAPI)	DK748103AA	40 PIN PDIP	1000	77	0

RELIABILITY MONITOR

TOTALS FOR: 0.8 μ m Single Poly, Single Metal FAIL RATE (Fits): 3 DEVICE HRS: 3.56E+08 0

RELIABILITY MONITOR

PROCESS: 1.2 µm Single Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1233	A5	APR '98	P22075	9752	CARSEM	DM740622AC	SOT-223	48	229	0
DS1233	A5	JUL '98	P22421	9828	CARSEM	DM819256AB	SOT-223	48	229	0
DS1267	A1	AUG '98	P22597	9824	ANAM-PI (AAPI)	DK745514AB	20 PIN TSSOP	48	229	0
DS1620	C1	MAR '98	P22173	9746	ALPHTK-BANGKOK(NSE	DJ723286AAC	8PN SOIC, 208MIL	48	232	0
DS1620	C1	DEC '97	P21529	9740	ALPHTK-BANGKOK(NSE	DJ724413AAD	8PN SOIC, 208MIL	48	237	0
DS1669	B3	NOV.'97	P21187	9744	OMEDATA	DD650016AAA	8PN SOIC, 208MIL	48	232	0
DS1669	B3	NOV.'97	P21187	9744	OMEDATA	DD650016AAA	8PN SOIC, 208MIL	48	38	0
DS5002	B3	APR 98 '	P22249	9806	CARSEM	DM743264AA	80 PIN PQFP	48	199	0
DS5002	B3	JUL '98	P22364	9822	CARSEM	DM808095AA	80 PIN PQFP	48	199	0
DS5002F	A3	JAN.'98	P21352	9738	CARSEM	DM720028AA	80 PIN PQFP	48	199	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1233	A5	APR '98	P22185	9752	CARSEM	DM740622AC	SOT-223	336	77	0
DS1233	A5	APR '98	P22185	9752	CARSEM	DM740622AC	SOT-223	1000	77	0
DS1620	C1	DEC '97	P21852	9740	ALPHTK-BANGKOK(NSE	DJ724413AAD	8PN SOIC, 208MIL	336	77	0
DS1620	C1	MAR '98	P22271	9746	ALPHTK-BANGKOK(NSE	DJ723286AAC	8PN SOIC, 208MIL	336	72	0
DS1620	C1	MAR '98	P22271	9746	ALPHTK-BANGKOK(NSE	DJ723286AAC	8PN SOIC, 208MIL	1000	72	0
DS1620	C1	DEC '97	P21852	9740	ALPHTK-BANGKOK(NSE	DJ724413AAD	8PN SOIC, 208MIL	1000	77	0

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DS1669	B3	NOV.'97	P21819	9744	OMEDATA	DD650016AAA	8PN SOIC, 208MIL	336	77	0
DS1669	B3	NOV.'97	P21819	9744	OMEDATA	DD650016AAA	8PN SOIC, 208MIL	1000	76	0
DS5002	B3	APR 98 '	P22319	9806	CARSEM	DM743264AA	80 PIN PQFP	336	77	0
DS5002	B3	APR 98 '	P22319	9806	CARSEM	DM743264AA	80 PIN PQFP	1000	77	0

TOTALS FOR: 1.2 μ m Single Poly, Single Metal FAIL RATE (Fits): 6 DEVICE HRS: 1.63E+08 0

RELIABILITY MONITOR

PROCESS: 2.0 µm Single Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2175S	D1	JUL '98	P22328	9811	ANAM-KOREA (AICL)	DN803119AAE	16 PIN SOIC	48	234	0
DS2180A	B3	MAY '98	P22196	9810	ANAM-KOREA (AICL)	DN752567AAB	44 PIN PLCC	48	236	0
DS2181A	A2	FEB.'98	P21699	9741	ANAM-KOREA (AICL)	DN728030AAB	44 PIN PLCC	48	237	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2175S	D1	JUL '98	P22402	9811	ANAM-KOREA (AICL)	DN803119AAE	16 PIN SOIC	336	77	0
DS2175S	D1	JUL '98	P22402	9811	ANAM-KOREA (AICL)	DN803119AAE	16 PIN SOIC	1000	77	0
DS2180A	B3	MAY '98	P22277	9810	ANAM-KOREA (AICL)	DN752567AAB	44 PIN PLCC	336	77	0
DS2180A	B3	MAY '98	P22277	9810	ANAM-KOREA (AICL)	DN752567AAB	44 PIN PLCC	1000	77	0
DS2181A	A2	FEB.'98	P21777	9741	ANAM-KOREA (AICL)	DN728030AAB	44 PIN PLCC	336	77	0
DS2181A	A2	FEB.'98	P21777	9741	ANAM-KOREA (AICL)	DN728030AAB	44 PIN PLCC	1000	77	0

TOTALS FOR: 2.0 µm Single Poly, Single Metal FAIL RATE (Fits): 10 DEVICE HRS: 9.18E+07 0

RELIABILITY MONITOR

PROCESS: 3.0 µm Single Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1210	C1	APR '98	P22232	9811	ANAM-KOREA (AICL)	DN752523AAC	16 PIN SOIC	48	233	0
DS1210	C1	JAN '98	P21776	9750	HYUNDAI-KOREA (HEI)	DN738347AAA	16 PIN SOIC	48	234	0
DS1210S	C1	JUL '98	P22330	9813	ANAM-KOREA (AICL)	DN801581AAC	16 PIN SOIC	48	234	0
DS1232	C1	APR '98	P22047	9805	ANAM-KOREA (AICL)	DN737280ABA	16 PIN SOIC	48	234	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1210	C1	APR '98	P22262	9811	ANAM-KOREA (AICL)	DN752523AAC	16 PIN SOIC	336	77	0
DS1210	C1	APR '98	P22262	9811	ANAM-KOREA (AICL)	DN752523AAC	16 PIN SOIC	1000	77	0
DS1210	C1	JAN '98	P22233	9750	HYUNDAI-KOREA (HEI)	DN738347AAA	16 PIN SOIC	336	77	0
DS1210	C1	JAN '98	P22233	9750	HYUNDAI-KOREA (HEI)	DN738347AAA	16 PIN SOIC	1000	77	0
DS1210S	C1	JUL '98	P22398	9813	ANAM-KOREA (AICL)	DN801581AAC	16 PIN SOIC	336	77	0
DS1210S	C1	JUL '98	P22398	9813	ANAM-KOREA (AICL)	DN801581AAC	16 PIN SOIC	1000	77	0
DS1232	C1	APR '98	P22145	9805	ANAM-KOREA (AICL)	DN737280ABA	16 PIN SOIC	336	77	0
DS1232	C1	APR '98	P22145	9805	ANAM-KOREA (AICL)	DN737280ABA	16 PIN SOIC	1000	77	0

TOTALS FOR: 3.0 µm Single Poly, Single Metal FAIL RATE (Fits): 7 DEVICE HRS: 1.23E+08 0

RELIABILITY MONITOR

PROCESS: 5.0 µm Single Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2108	B1	MAY '98	P22138	9741	ANAM-KOREA (AICL)	DN729121ABA	24 PIN SOIC	48	234	0
DS2108	B1	AUG '98	P22456	9747	ANAM-KOREA (AICL)	DN722653BA	24 PIN SOIC	48	234	0
DS2108	B1	FEB.'98	P21556	9740	ANAM-KOREA (AICL)	DN729120AAC	24 PIN SOIC	48	234	0
DS232	B3	JUN '98	P22122	9809	OMEDATA	DD747723AB	16 PIN PDIP	48	234	0
DS232	B3	MAR '98	P21726	9809	OMEDATA	DD747723AA	16 PIN PDIP	48	234	0
DS232	B3	SEPTEM	P22499	9809	OMEDATA	DD747726AAA	16 PIN PDIP	48	234	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2108	B1	FEB.'98	P21690	9740	ANAM-KOREA (AICL)	DN729120AAC	24 PIN SOIC	336	77	0
DS2108	B1	MAY '98	P22153	9741	ANAM-KOREA (AICL)	DN729121ABA	24 PIN SOIC	336	77	0
DS2108	B1	AUG '98	P22484	9747	ANAM-KOREA (AICL)	DN722653BA	24 PIN SOIC	336	77	0
DS2108	B1	FEB.'98	P21690	9740	ANAM-KOREA (AICL)	DN729120AAC	24 PIN SOIC	1000	77	0
DS2108	B1	AUG '98	P22484	9747	ANAM-KOREA (AICL)	DN722653BA	24 PIN SOIC	1000	77	0
DS2108	B1	MAY '98	P22153	9741	ANAM-KOREA (AICL)	DN729121ABA	24 PIN SOIC	1000	77	0
DS232	B3	JUN '98	P22166	9809	OMEDATA	DD747723AB	16 PIN PDIP	336	77	0
DS232	B3	MAR '98	P21751	9809	OMEDATA	DD747723AA	16 PIN PDIP	336	77	0
DS232	B3	JUN '98	P22166	9809	OMEDATA	DD747723AB	16 PIN PDIP	1000	77	0
DS232	B3	MAR '98	P21751	9809	OMEDATA	DD747723AA	16 PIN PDIP	1000	77	0

RELIABILITY MONITOR

TOTALS FOR: 5.0 μ m Single Poly, Single Metal FAIL RATE (Fits): 9 DEVICE HRS: 1.02E+08 0